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(12) **United States Design Patent**
Hagmann et al.

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(45) **Date of Patent: ** Dec. 17, 2013**

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(54) **TEST FIXTURE FOR SCANNING PROBE MICROSCOPY**

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(**) Term: **14 Years**

(21) Appl. No.: **29/410,757**

(22) Filed: **Jan. 11, 2012**

(51) **LOC (9) Cl.** **16-06**

(52) **U.S. Cl.**
USPC **D16/131**

(58) **Field of Classification Search**
USPC D10/46; D16/131; 73/105; 250/305, 250/310, 311, 307, 491.1; 310/311–328; 359/368; 385/134, 137; 850/6, 17, 26, 850/33, 19, 9, 22, 40, 7, 3, 1, 13, 18; 977/852, 861, 869, 870
See application file for complete search history.

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Primary Examiner — Antoine D Davis

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(57) **CLAIM**

The ornamental design for a test fixture for scanning probe microscopy, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of the test fixture for scanning probe microscopy, installed on an unclaimed three-axis stage.

FIG. **2** is an alternate perspective view of the test fixture for scanning probe microscopy of FIG. **1**.

FIG. **3** rear elevation of the test fixture for scanning probe microscopy of FIG. **1**.

FIG. **4** is a perspective view of the test fixture for scanning probe microscopy.

FIG. **5** is a left elevation of the test fixture for scanning probe microscopy of FIG. **4**.

FIG. **6** is a right elevation of the test fixture for scanning probe microscopy of FIG. **4**.

FIG. **7** is a front elevation of the armature of the test fixture for scanning probe microscopy of FIG. **4**.

FIG. **8** is a front elevation of the stage of the test fixture for scanning probe microscopy of FIG. **4**.

FIG. **9** is a rear elevation of the armature of test fixture for scanning probe microscopy of FIG. **4**.

FIG. **10** is a rear elevation of the stage of the test fixture for scanning probe microscopy of FIG. **4**.

FIG. **11** is a top plan view of the armature of the test fixture for scanning probe microscopy of FIG. **4**.

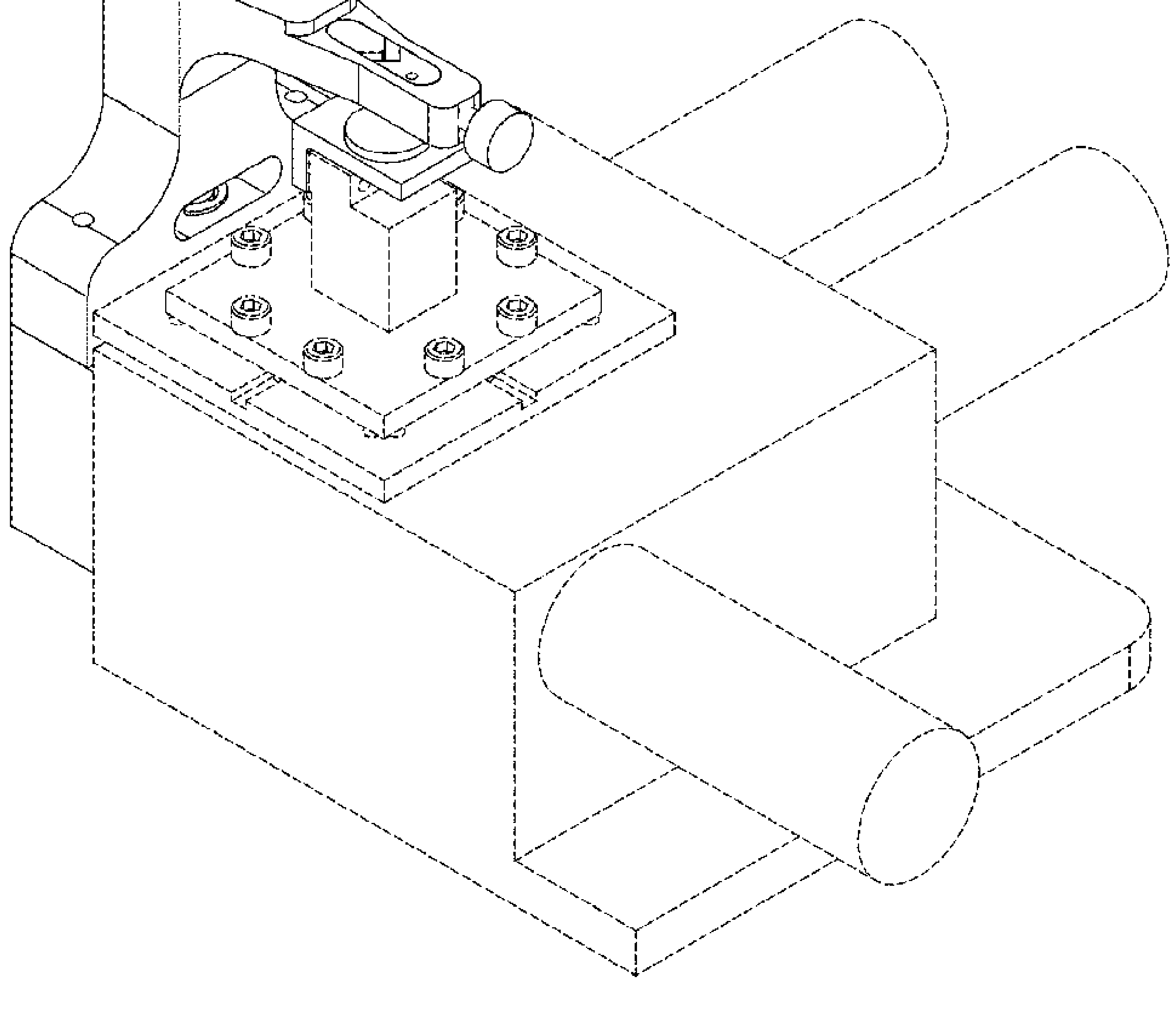
FIG. **12** is a top plan view of the stage of the test fixture for scanning probe microscopy of FIG. **4**.

FIG. **13** is a bottom plan view of the armature of the test fixture for scanning probe microscopy of FIG. **4**; and,

FIG. **14** is a bottom plan view of the stage of the test fixture for scanning probe microscopy of FIG. **4**.

The broken lines in FIGS. **1**, **2**, and **3** depict environment and do not form a basis of the claimed design.

1 Claim, 5 Drawing Sheets



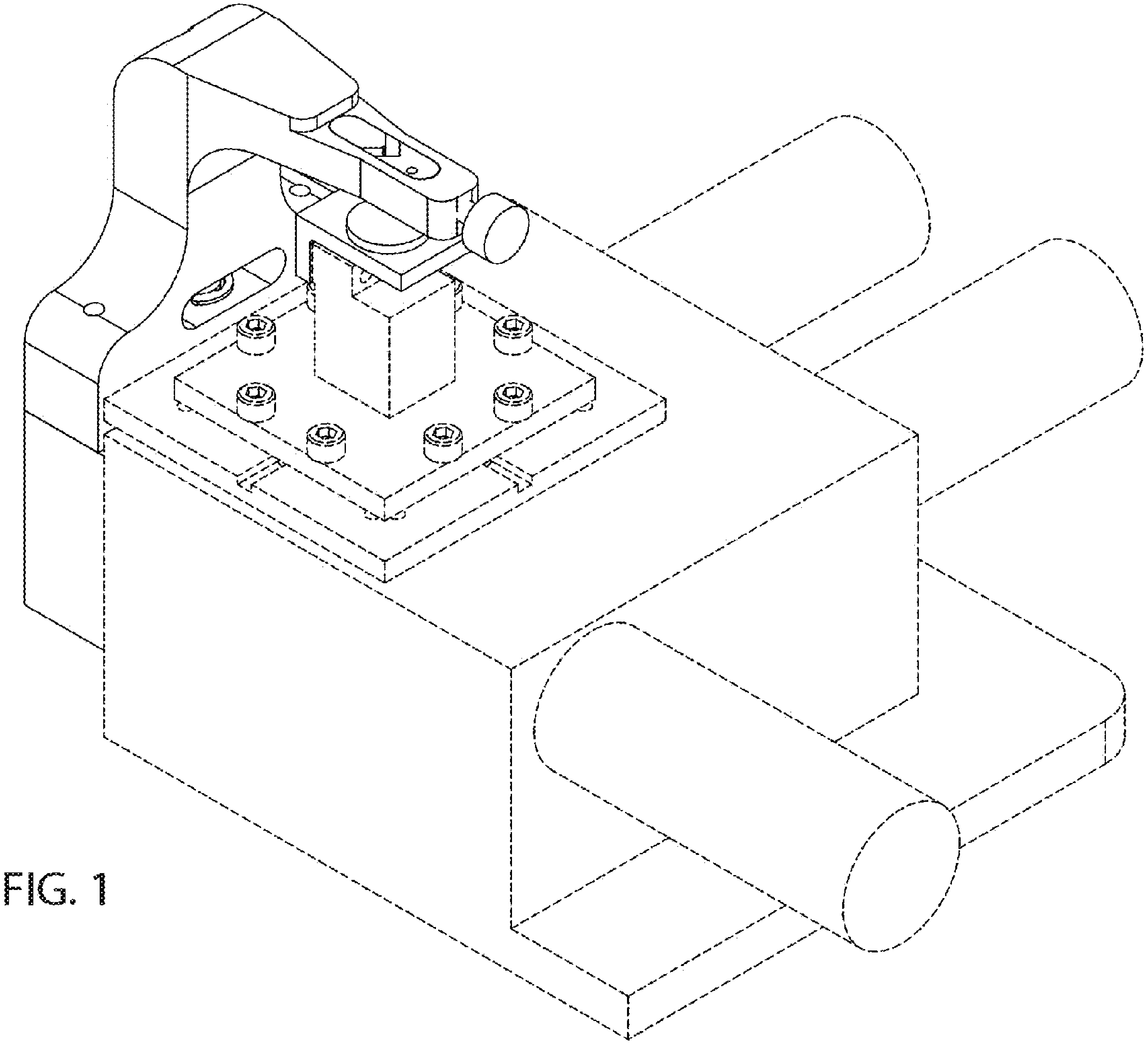


FIG. 1

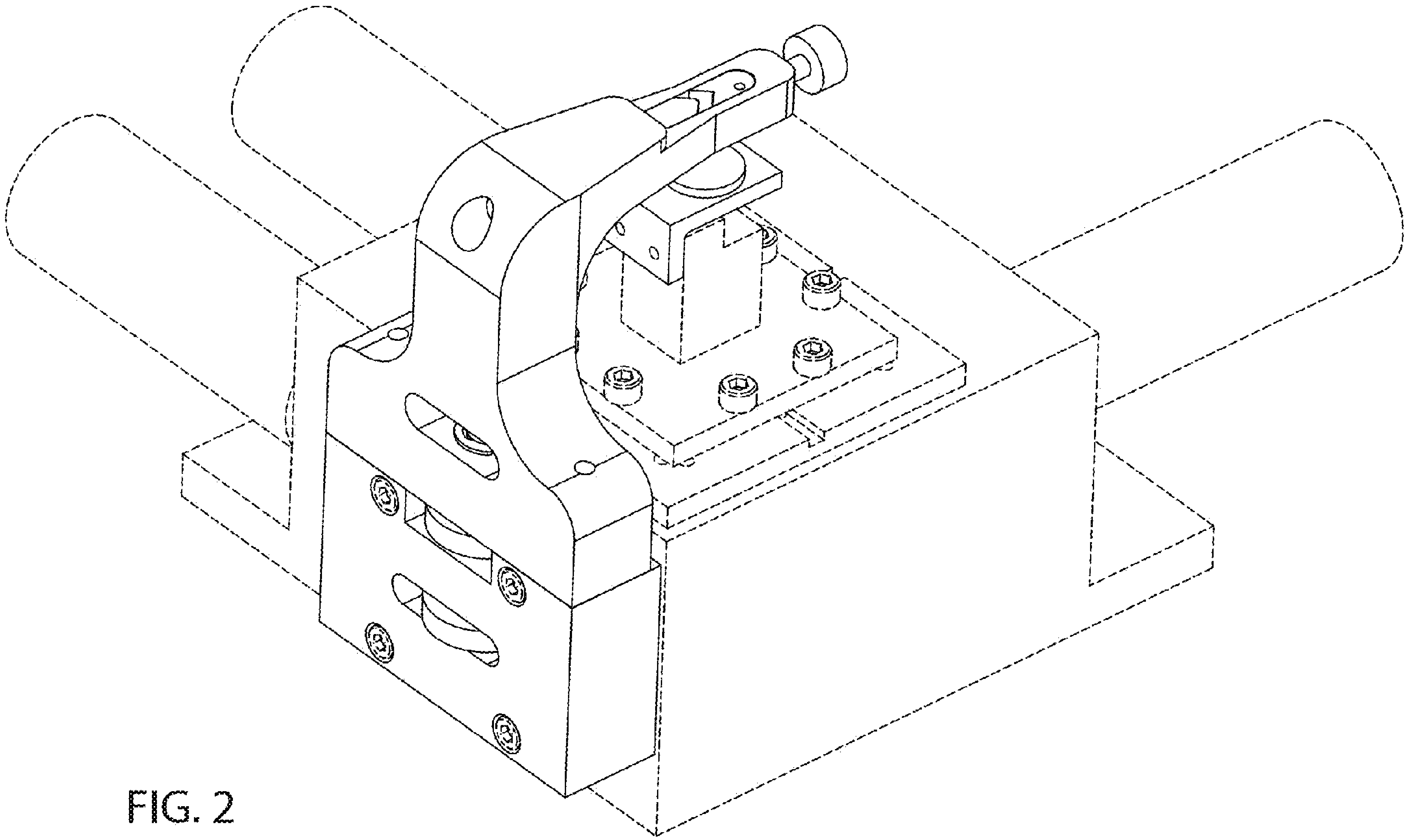


FIG. 2

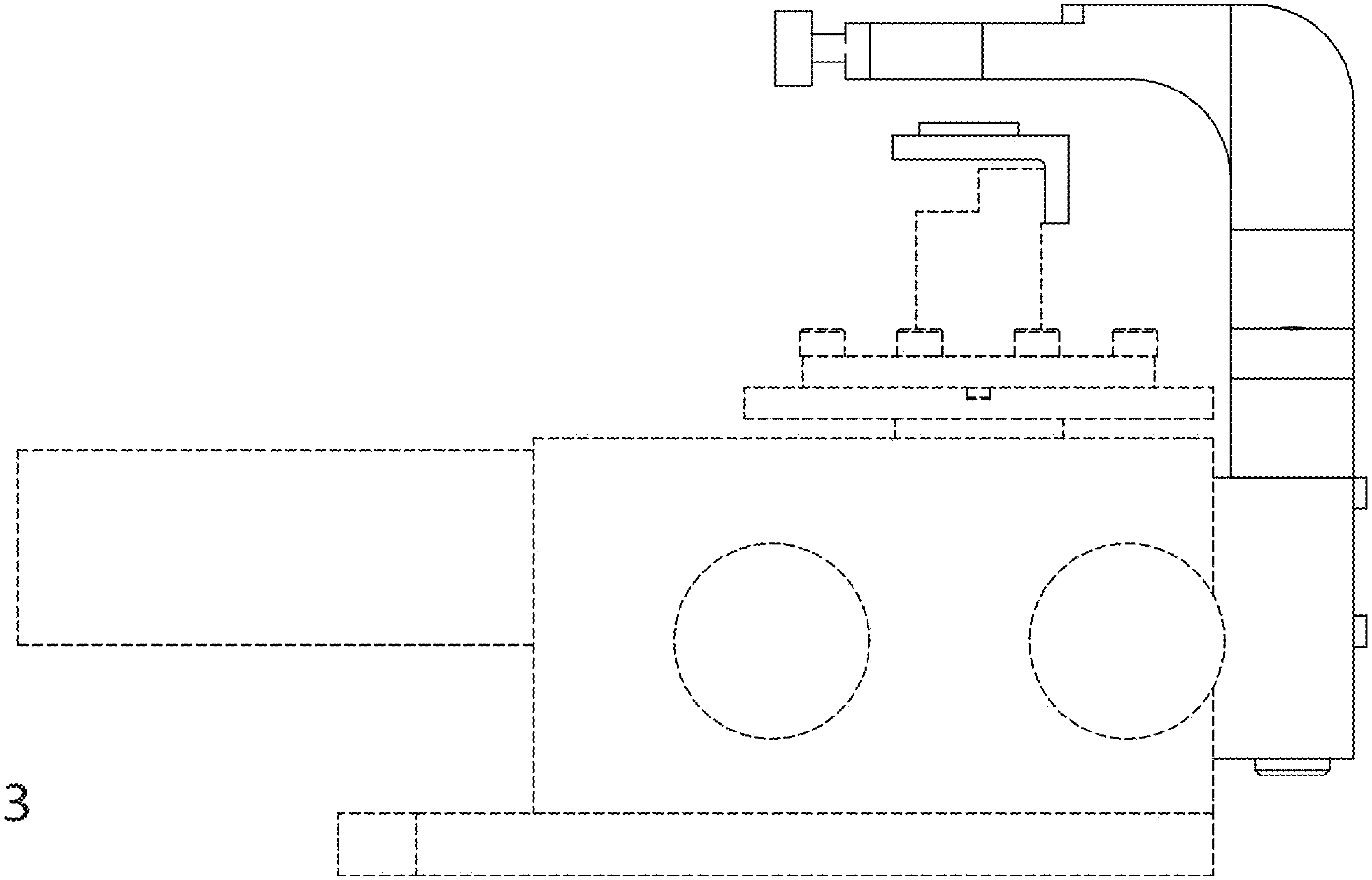


FIG. 3

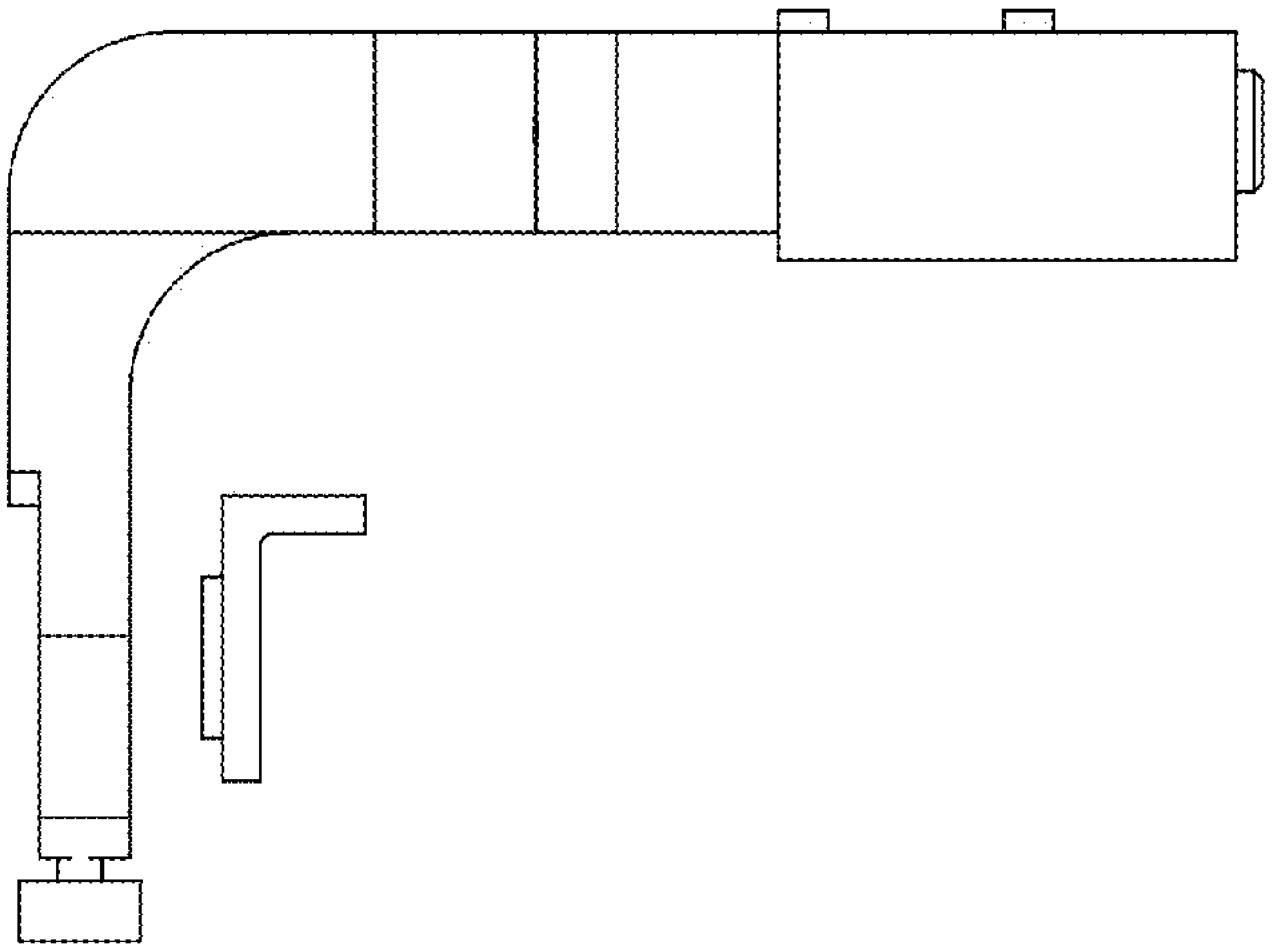


FIG. 6

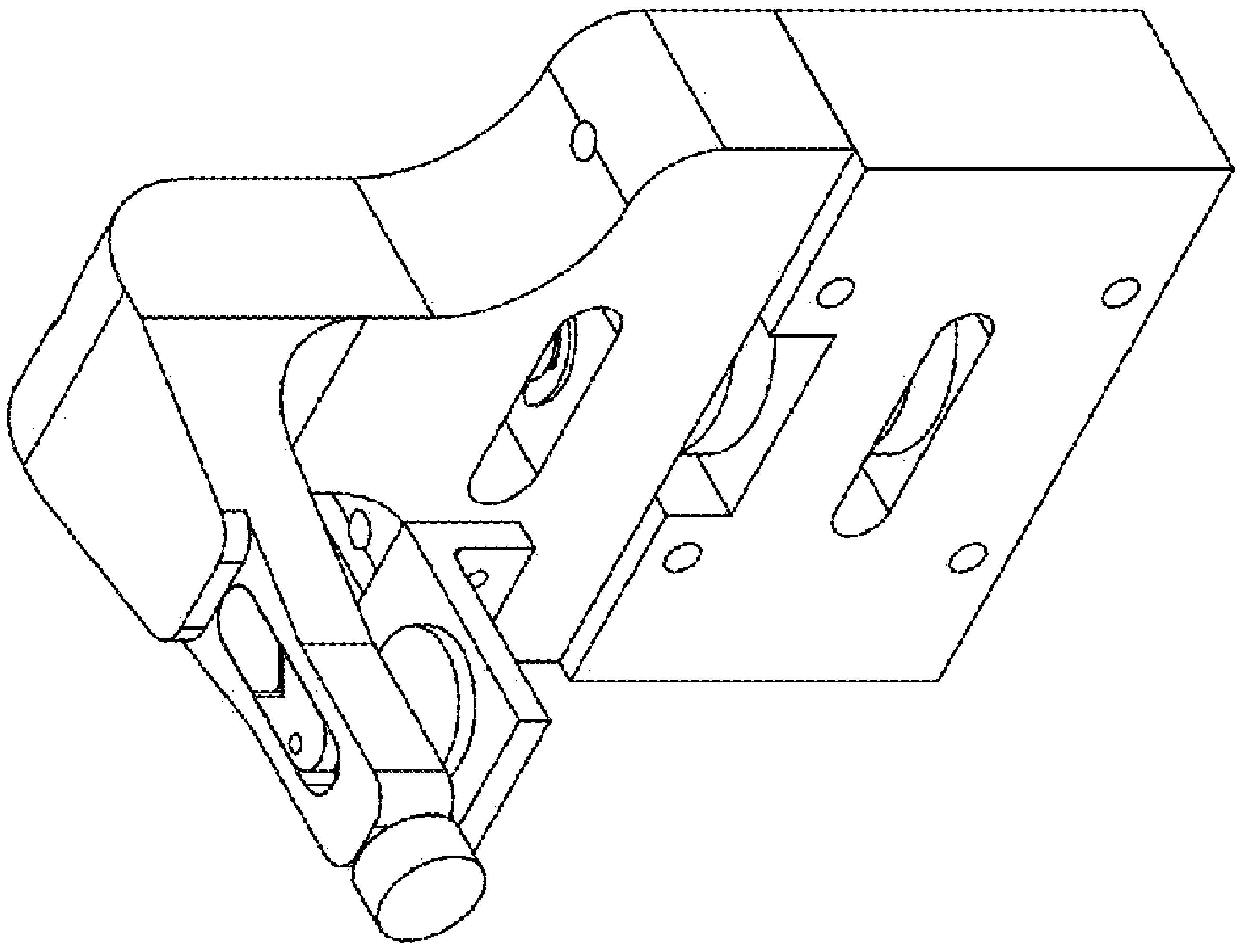


FIG. 4

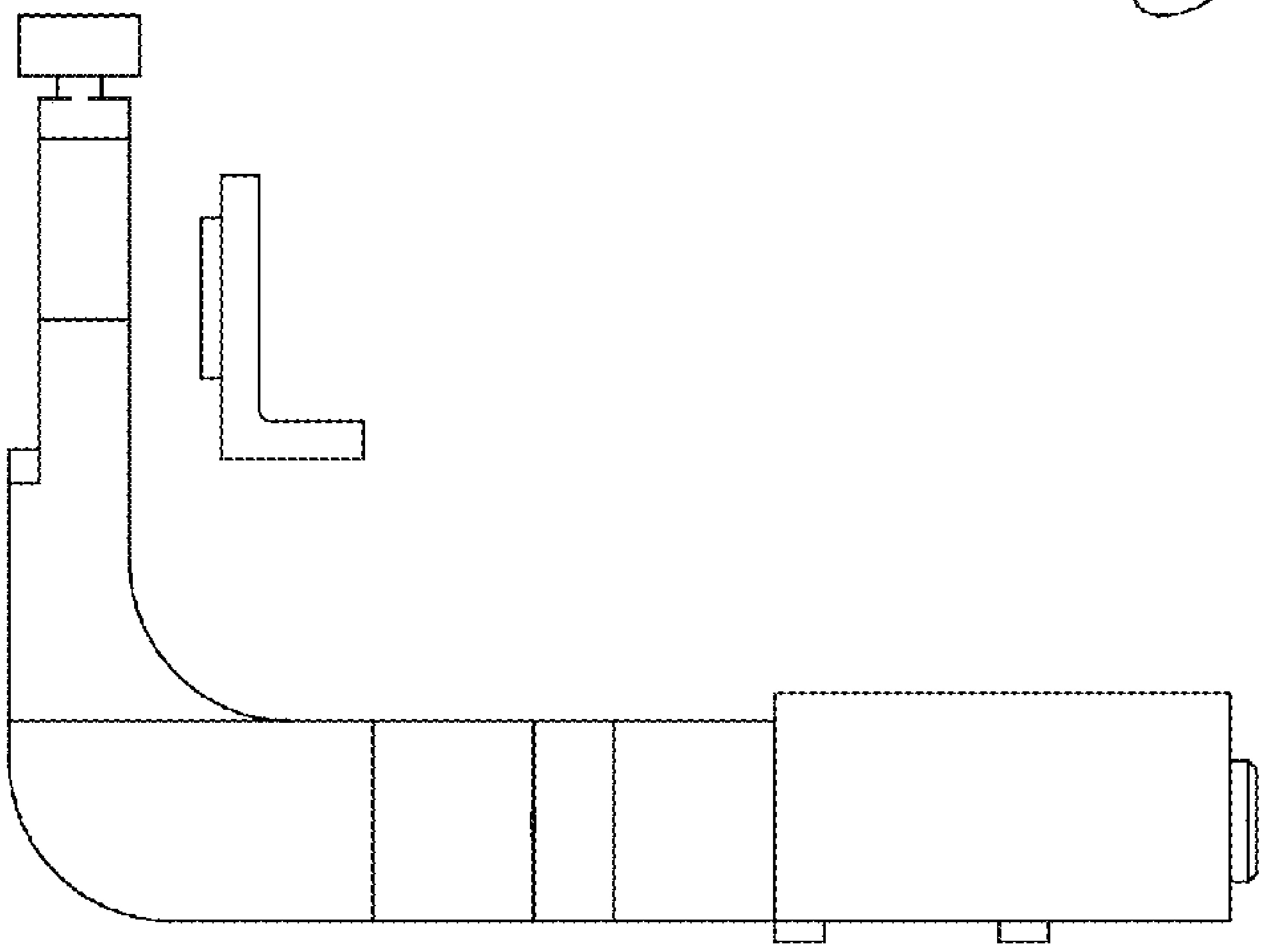


FIG. 5

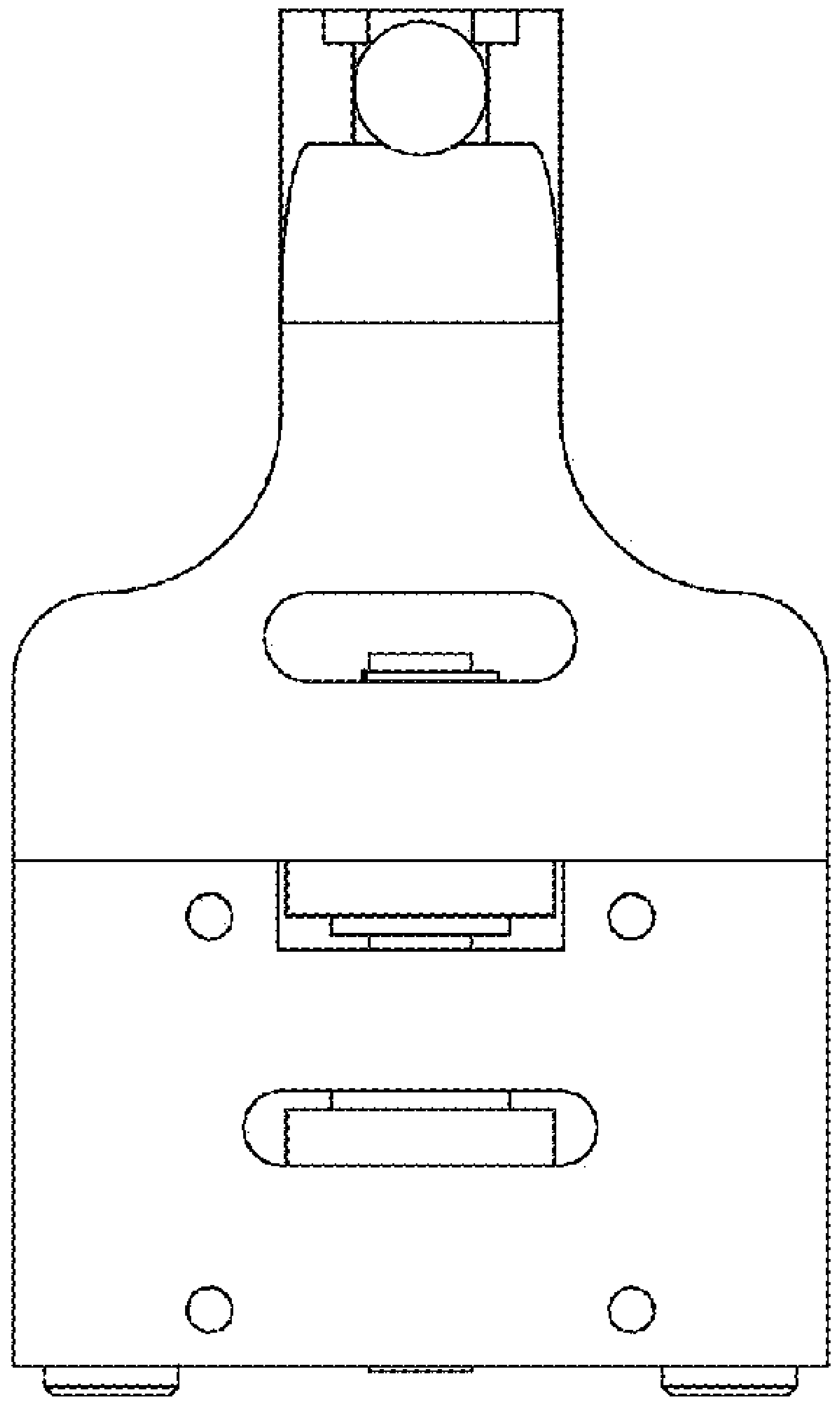


FIG. 7

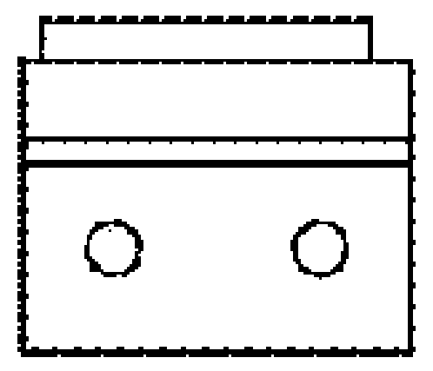


FIG. 8

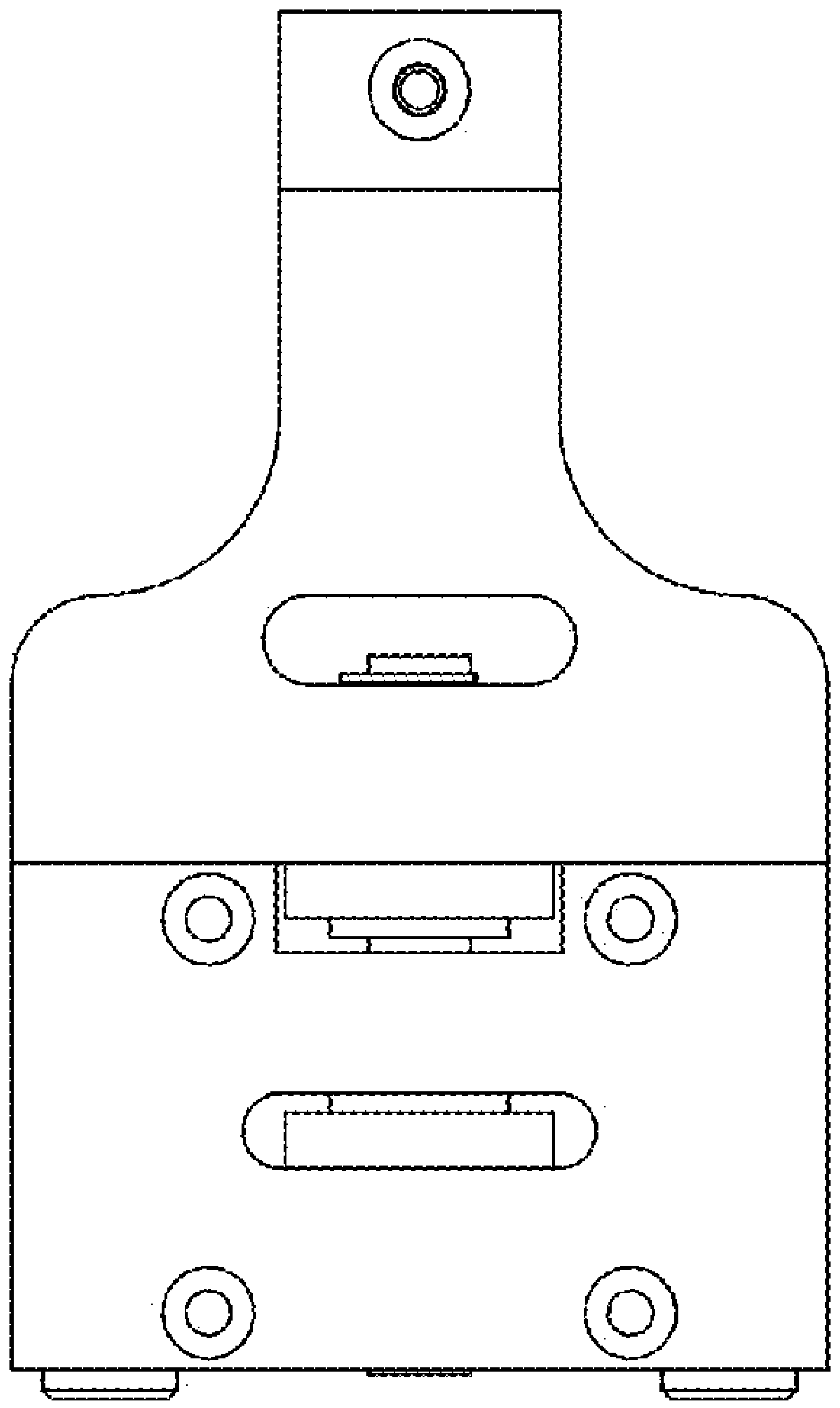


FIG. 9

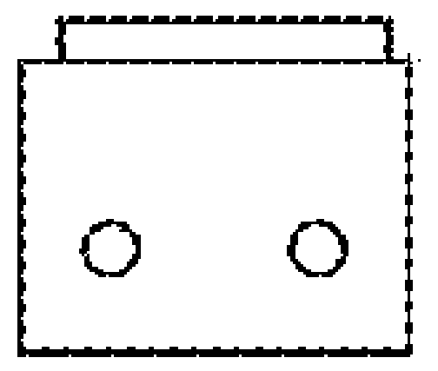


FIG. 10

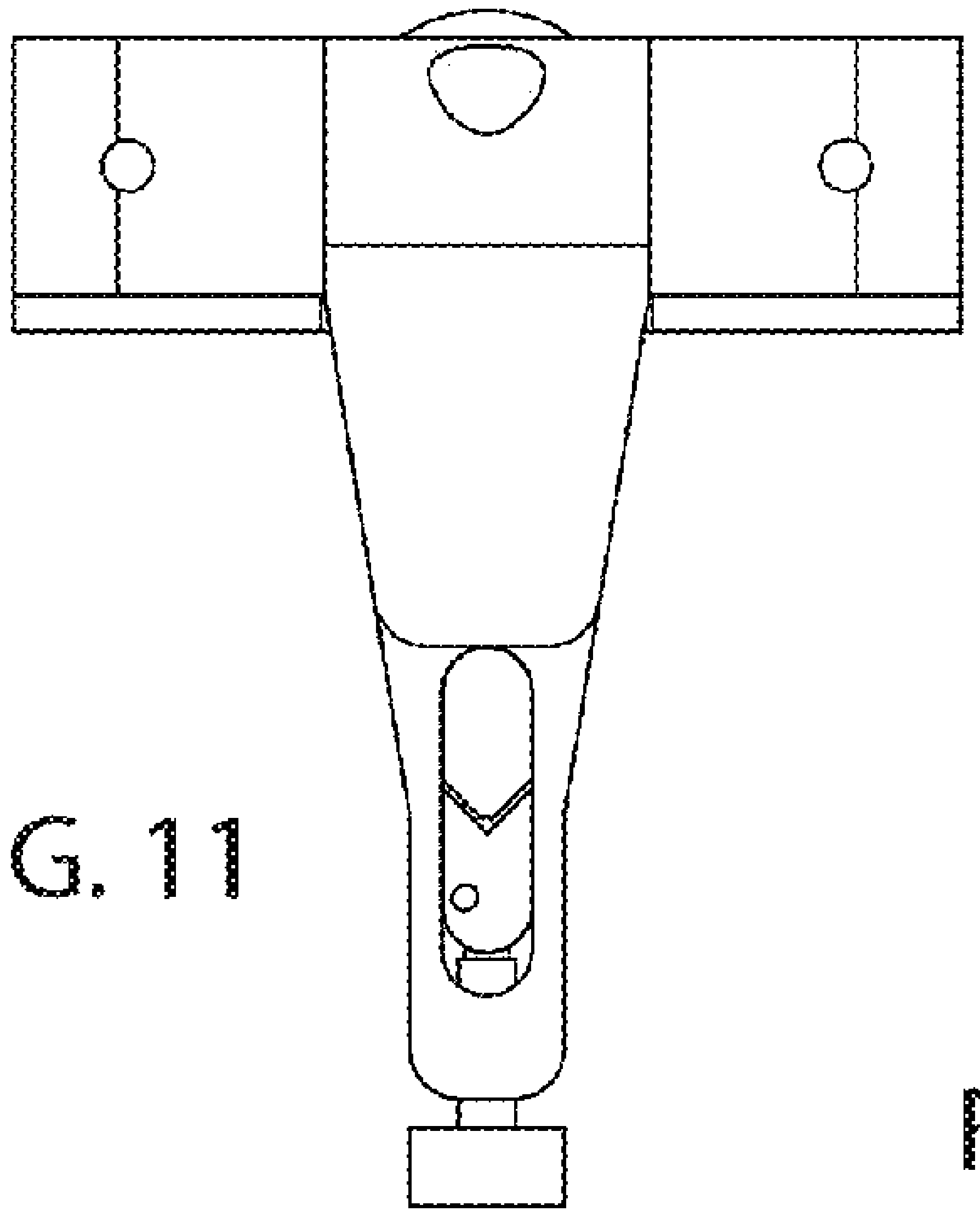


FIG. 11

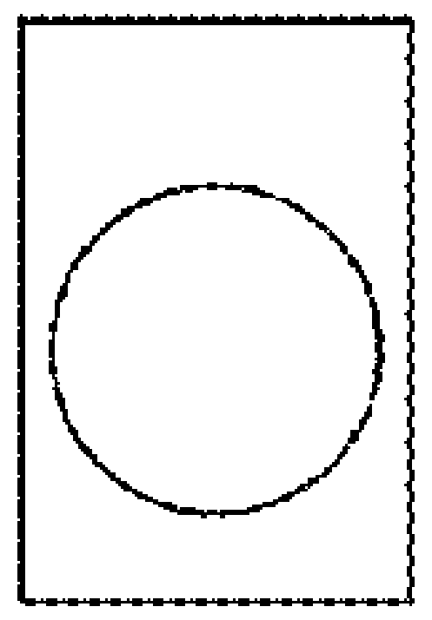


FIG. 12

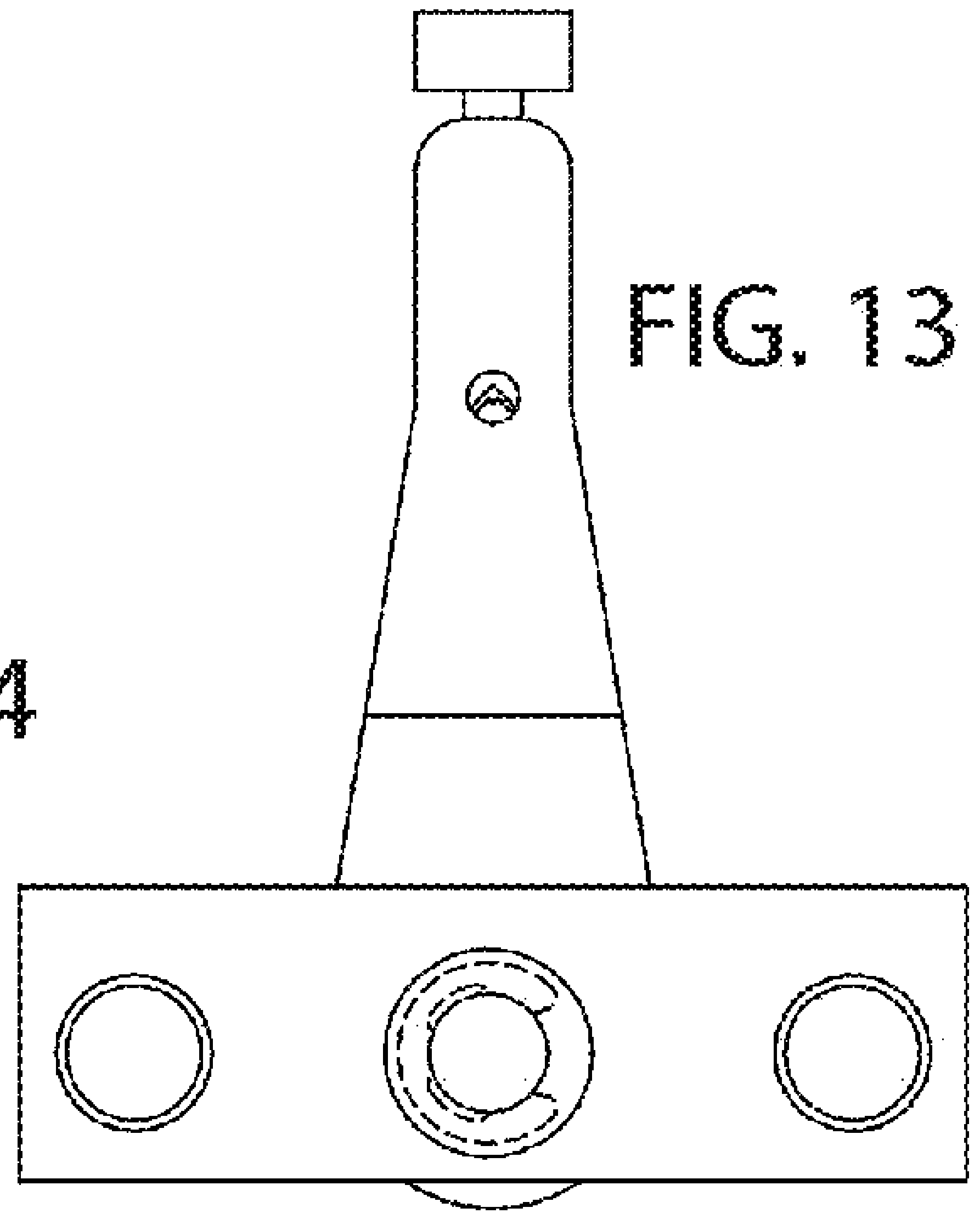


FIG. 13

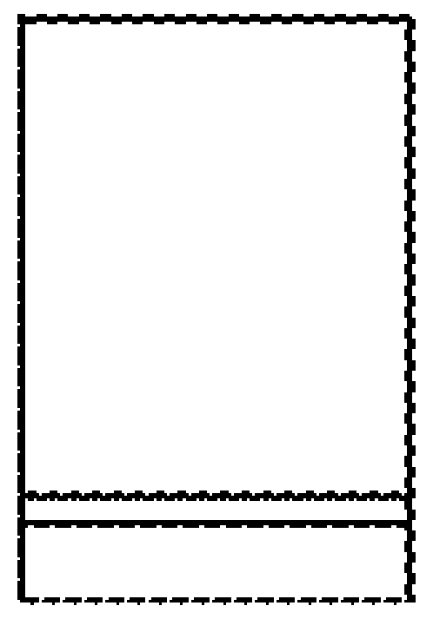


FIG. 14